eco

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The Powerhouse, PO Box 45, Queens Road, St. Helier, Jersey, JE4 8NY

G59-3 PARALLEL GENERATOR COMMISSIONING TESTS FORM

NON-TYPE TESTED GENERATING UNIT IN ADDITION TO THOSE REQUIRED IN APPENDIX 13.2

OVER AND UNDER VOLTAGE PROTECTION TESTS LV													
				Cal	ibration aı	nd Accura	ıcy Tests						
Phase	Setting	Time Delay		Pickup Voltage				Time Delay Setting plus or minus 4V					
Stage 1	Over Volto	ıge	Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer mit	Meas Valu		Upper Limit	Result
L1 - N	262.2V					Pass/Fail							Pass/Fail
L2 - N	230V	1.0s	258.75		265.65	Pass/Fail	266.2	1	.0s			1.1s	Pass/Fail
L3 - N	system					Pass/Fail							Pass/Fail
Stage 2	Over Volto	ıge	Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer mit			Upper Limit	Result
L1 - N	273.7V					Pass/Fail							Pass/Fail
L2 - N	230V	0.5s	270.25		277.15	Pass/Fail	277.7	0.5s				0.6s	Pass/Fail
L3 - N	system					Pass/Fail							Pass/Fail
Stage 1	Under Vol	tage	Lower Limit	'' Kocult		Test Value		ower Measured Limit Value			Upper Limit	Result	
L1 - N	200.1V				Pass/Fail							Pass/Fail	
L2 - N	230V	2.5s	196.65		203.55	Pass/Fail		2.5s				2.6s	Pass/Fail
L3 - N	system					Pass/Fail							Pass/Fail
Stage 2	Under Vol	tage	Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer mit	Meas Valu		Upper Limit	Result
L1 - N	184.0V					Pass/Fail							Pass/Fail
L2 - N	230V	0.5s	180.55		187.45	Pass/Fail	180	0	.5s			0.6s	Pass/Fail
L3 - N	system					Pass/Fail							Pass/Fail
					Stabi	lity Tests							
Tes	t Descriptio	n	Setting	Time Delay	Test Condition (3-Phase Value)		Test Voltage phases ph-		Test Duration		Confirm No Trip		Result
Inside No	rmal band				< OV Stage 1		258.2V		5.00s				Pass/Fail
Stage 1 Over Voltage 262.2V 1.0s		1.0s	> OV S	Stage 1	269.7V	269.7V 0.		0.95s			Pass/Fail		
Stage 2 Over Voltage 273.7V 0.5s		0.5s	> OV S	Stage 2	277.7V C		0.	0.45s			Pass/Fail		
Inside No	rmal band				> UV S	itage 1	204.1V		5.00s			Pass/Fail	
Stage 1	Under Vol	tage	200.1V	2.5s	< UV S	tage 1			2.	2.45s			Pass/Fail
Stage 2	Under Vol	tage	184.0V	0.5s	< UV Stage 2		180V		0.45s			Pass/Fail	

	OVER	AND U	NDER VOL	TAGE PROTE	CTION TE	STS HV RI	EFERENCED	ТО	110V	PH-PH	VT O	UTPUT			
				Cal	ibration a	nd Accura	cy Tests								
Phase	Setting	Time Delay		Pickup Voltage				Time Delay measured value plus or minus 2V							
Stage 1	Over Volta	ige	Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer imit	Measi Valu		Upper Limit	Result		
L1 - L2	1011/					Pass/Fail							Pass/Fail		
L2 - L3	121V 110V_VT	1.0s	119.35		122.65	Pass/Fail	Measured value plus 2V	1	.0s			1.1s	Pass/Fail		
L3 - L1	secondary					Pass/Fail							Pass/Fail		
Stage 2	Over Volta	ige	Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer imit	Meası Valu		Upper Limit	Result		
L1 - L2	10 4 0) 4					Pass/Fail							Pass/Fail		
L2 - L3	124.3V 110V VT secondary	0.5s	122.65		125.95	Pass/Fail	value plus	Measured value plus 0.5s			0.6s		Pass/Fail		
L3 - L1	secondary					Pass/Fail	2 V						Pass/Fail		
Stage 1	Stage 1 Under Voltage		Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer imit	Meası Valu		Upper Limit	Result		
L1 - L2	05.701/	_{∕T} 2.5s	2.5s				Pass/Fail	Measured						Pass/Fail	
L2 - L3	95.70V 110V VT secondary			94.05		97.35	Pass/Fail		2.5s				2.6s	Pass/Fail	
L3 - L1	secondary					Pass/Fail		Z V					Pass/Fail		
Stage 2	Stage 2 Under Voltage		Lower Limit	Measured Value	Upper Limit	Result	Test Value		wer imit	Meası Valı		Upper Limit	Result		
L1 - L2	00.001/					Pass/Fail				0.5s					Pass/Fail
L2 - L3	88.00V 110V VT secondary	0.5s	86.35		89.65	Pass/Fail	value minus							0.6s	Pass/Fail
L3 - L1	secondary					Pass/Fail	2 4						Pass/Fail		
Stability Tests															
Tes	Test Description Setting Time Test Cond Delay (3-Phase V			Test Voltage all phases ph-n		Test Duration		Confirm No Trip		Result					
Inside No	ormal band				< OV Stage 1		119V		5.00s				Pass/Fail		
Stage 1 Over Voltage 121V 1.0s		> OV Stage 1		122.3V		0.95s				Pass/Fail					
Stage 2 Over Voltage		ige	124.3V	0.5s	> OV 9	Stage 2	126.3V		0.45s				Pass/Fail		
Inside Normal band					> UV S	Stage 1	97.7V		5.00s				Pass/Fail		
Stage 1	Under Volt	age	95.7V	2.5s	< UV S	Stage 1	90V		2.45s				Pass/Fail		
Stage 2	Under Volt	age	88V	0.5s	< UV Stage 2		86V		0.	0.45s			Pass/Fail		

		C	VER AND L	JNDI	ER FRI	EQUENCY F	PROTECTIO	N TES	TS				
			C	Calibr	ration	and Accura	acy Tests						
Setting	Time Delay		Pickup Fi	requ	ency		Time Delay						
Stage 1 Over F	requency	equency Lower Measure Limit Value			per mit	Result	Freq step	Low Lim		Measured Value	Upper Limit	Result	
51.5Hz	90s	51.40		51	.60	Pass/Fail	51.2- 51.8Hz	90.	0s		90.9s	Pass/Fail	
Stage 2 Over Frequency		Lower Limit	Measured Value	Upper Limit		Result	Freq step	Low Lim		Measured Value	Upper Limit	Result	
52Hz	0.5s	51.90		52	2.10	51.2- 51.8Hz	51.7- 52.3Hz	0.5	0s		0.60s	Pass/Fail	
Stage 1 Under Frequency		Lower Limit	Measured Value	Upper Limit		Result	Freq step	Low Lim		Measured Value	Upper Limit	Result	
47.5Hz	20s	47.40		47	7.60	51.2- 51.8Hz	47.8- 47.2Hz	20.	0s		20.2s	Pass/Fail	
Stage 2 Under Frequency		Lower Limit	Measured Value		per mit	Result	Freq step	Low Lim		Measured Value	Upper Limit	Result	
47Hz	0.5s	46.90		4	7.1	51.2- 51.8Hz	47.3- 46.7Hz	0.5	0s		0.60s	Pass/Fail	
					Sto	bility Tests							
Test Desc	cription	Setting	Time Delay	Time Test		Condition	Test Frequency		Di	Test uration	Confirm No Trip	Result	
Inside Normal I	band				< OF Stage 1		51.3Hz		120s			Pass/Fail	
Stage 1 Over Frequency		51.5H	z 90s		> C	F Stage 1	51.7Hz		89.0s			Pass/Fail	
Stage 2 Over Frequency		52Hz	0.5s		> C	F Stage 2	52.2Hz		0.45s			Pass/Fail	
Inside Normal I	band				> U	IF Stage 1	47.7Hz			30s		Pass/Fail	
Stage 1 Unde	r Frequency	47.5H	z 20s		< L	IF Stage 1	47.3H	z		19.5s		Pass/Fail	
Stage 2 Under Frequency		47Hz	0.5s		< L	F Stage 2	46.8Hz		(0.45s		Pass/Fail	

LOSS-OF-MAINS (LOM) PROTECTION TESTS - ROCOF								
Calibration and Accuracy Tests								
Ramp in range 49.5-50.5Hz	Time De F= +0.05Hz/	,	ting					
Setting = 0.125 / 0.20 Hzs ⁻¹	Lower Limit	Measured Value	Upper Limit	Result	Test Condition	Measured Value	Upper Limit	Result
Increasing Frequency	0.120 0.195		0.130 0.205	Pass/Fail	0.175 Hzs ⁻¹ 0.25 Hzs ⁻¹		<0.5s	Pass/Fail
Reducing Frequency	0.120 0.195		0.130 0.205	Pass/Fail	0.175 Hzs ⁻¹ 0.25 Hzs ⁻¹		<0.5s	Pass/Fail
Stability Tests								
Ramp in range 49.5-50.5Hz	Test Condition		Test frequency ramp		Test Duration	Confirm	No Trip	Result
Inside Normal band	< RoCoF (increasing f)		Higher of 0.12 Hzs ⁻¹		5.0s			Pass/Fail
Inside Normal band < RoCoF (reducing f)		or ROCOF - 0.01 Hzs ⁻¹		5.0s			Pass/Fail	

Additional	Comments	/ Observations:
Audilioliui	COHIHICHIS	/ Observations.

	LOSS-OF-MAINS (LOM) PROTECTION TESTS - VECTOR SHIFT											
		Calibra	ition and Ad	curacy Test	S							
Vector Shift	ector Shift Pickup (± 0.5 degree)						Time Delay Vector shift = 2 deg above setting					
Setting = 6 / 12 degrees	Lower Limit	Measured Value	Upper Limit	Result	Test Condition	Measured Value	Upper Limit	Result				
Vector Shift : Lagging Angle	5.5 11.5		6.5 12.5	Pass/Fail	8 deg 14 deg		<0.5s	Pass/Fail				
Vector Shift : Leading Angle	5.5 11.5		6.5 12.5	Pass/Fail	8 deg 14 deg		<0.5s	Pass/Fail				
			Stability To	ests								
Test Description	Test Condition		Test vector shift		Test Duration	Confirm No Trip		Result				
Inside Normal band	< Vector Shift (Lagging f)		Higher of 5 degrees or vector shift -1 degre		e			Pass/Fail				
Inside Normal band		tor Shift ding f)	=					Pass/Fail				

DECLARATION – TO BE COMPLETED BY GENERATOR OR GENERATORS APPOINTED TECHNICAL REPRESENTATIVE							
I declare that the Generating Unit and the installation comply with the requirements of G59/3 and the additional commissioning checks noted above have been successfully completed in addition to those required for all Generating Unit installations (see Appendix 13.2)							
Signature	Date						
Position							
DECLARATION – TO BE COMPLETED BY DNO WITNESSING REPRESENTATIVE							
I confirm that I have witnessed the tests in this document on behalf of							
	and that the results are an accurate record of the tests						

Date

Signature